

ABSTRACT OF THE DISCLOSURE

A method of screening defects includes steps of: (a) measuring a quiescent current at a first supply voltage for each of a plurality of devices; (b) measuring a quiescent current at a second supply voltage for each of the plurality of devices; (c) generating a plot of the quiescent current measured at the first supply voltage vs. the quiescent current measured at the second supply voltage for each of the plurality of devices; (d) determining a range of intrinsic variation of quiescent current in the plot; and (e) identifying any of the plurality of devices corresponding to a measurement plotted outside the range of intrinsic variation as defective.